### **AUTOMOTIVE GRADE**

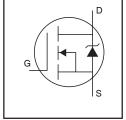


# AUIRFB3207

HEXFET® Power MOSFET

### **Features**

- Advanced Process Technology
- Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Tjmax
- Lead-Free, RoHS Compliant
- Automotive Qualified \*



V <sub>(BR)DSS</sub>	75V
R <sub>DS(on)</sub> typ.	3.6m $Ω$
max.	<b>4.5m</b> $Ω$
I <sub>D (Silicon Limited)</sub>	<b>170A</b> ①
D (Package Limited)	75A



G	D	S
Gate	Drain	Source

### **Description**

Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating . These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide variety of other applications.

### **Absolute Maximum Ratings**

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature  $(T_A)$  is 25°C, unless otherwise specified.

	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited)	170⊕	
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, VGS @ 10V (Silicon Limited)	120①	A
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Package Limited)	75	7 ^
I <sub>DM</sub>	Pulsed Drain Current ②	720	
P <sub>D</sub> @T <sub>C</sub> = 25°C	Maximum Power Dissipation	300	W
	Linear Derating Factor	2.0	W/°C
$V_{GS}$	Gate-to-Source Voltage	± 20	V
E <sub>AS</sub>	Single Pulse Avalanche Energy (Thermally limited) ③	910	mJ
I <sub>AR</sub> Avalanche Current ②		See Fig. 14, 15, 16a, 16b,	Α
E <sub>AR</sub>	Repetitive Avalanche Energy		mJ
dV/dt	Peak Diode Recovery ®	5.8	V/ns
T <sub>J</sub>	Operating Junction and	-55 to + 175	
T <sub>STG</sub>	Storage Temperature Range		∘c
	Soldering Temperature, for 10 seconds	300	7
	(1.6mm from case)		
	Mounting torque, 6-32 or M3 screw	10lb·in (1.1N·m)	

### Thermal Resistance

Thormal Hoolotanoo							
	Parameter	Тур.	Max.	Units			
$R_{\theta JC}$	Junction-to-Case ®		0.50				
$R_{\theta CS}$	Case-to-Sink, Flat Greased Surface, TO-220	0.50		°C/W			
$R_{\theta JA}$	Junction-to-Ambient, TO-220		62				

HEXFET® is a registered trademark of International Rectifier.

<sup>\*</sup>Qualification standards can be found at http://www.irf.com/

### Static Electrical Characteristics @ $T_J = 25$ °C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	75			V	$V_{GS} = 0V, I_{D} = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.069	—	V/°C	Reference to 25°C, I <sub>D</sub> = 1mA@
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance		3.6	4.5	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 75A ⑤
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$
gfs	Forward Transconductance	150			S	$V_{DS} = 50V, I_{D} = 75A$
$R_G$	Gate Input Resistance		1.2		Ω	f = 1MHz, open drain
I <sub>DSS</sub>	Drain-to-Source Leakage Current			20		$V_{DS} = 75V$ , $V_{GS} = 0V$
				250	μΑ	$V_{DS} = 75V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I <sub>GSS</sub>	Gate-to-Source Forward Leakage			200	nΛ	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage			-200	nA	$V_{GS} = -20V$

### Dynamic Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$Q_g$	Total Gate Charge		180	260		I <sub>D</sub> = 75A
$Q_{gs}$	Gate-to-Source Charge		48		nC	$V_{DS} = 60V$
$Q_{gd}$	Gate-to-Drain ("Miller") Charge		68		1	V <sub>GS</sub> = 10V ⑤
t <sub>d(on)</sub>	Turn-On Delay Time		29			$V_{DD} = 48V$
t <sub>r</sub>	Rise Time		120			$I_D = 75A$
t <sub>d(off)</sub>	Turn-Off Delay Time		68		ns	$R_G = 2.6\Omega$
t <sub>f</sub>	Fall Time		74		1	V <sub>GS</sub> = 10V ⑤
C <sub>iss</sub>	Input Capacitance		7600			$V_{GS} = 0V$
C <sub>oss</sub>	Output Capacitance		710			$V_{DS} = 50V$
C <sub>rss</sub>	Reverse Transfer Capacitance		390		рF	f = 1.0MHz
C <sub>oss</sub> eff. (ER)	Effective Output Capacitance (Energy Related) ⑦		920			$V_{GS} = 0V$ , $V_{DS} = 0V$ to $60V$ , See Fig.11
C <sub>oss</sub> eff. (TR)	Effective Output Capacitance (Time Related)®		1010			$V_{GS} = 0V$ , $V_{DS} = 0V$ to $60V$ , See Fig. 5

### **Diode Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			170①		MOSFET symbol
	(Body Diode)			1700		showing the
I <sub>SM</sub>	Pulsed Source Current			720	] ^	integral reverse
	(Body Diode) © ⑦			720		p-n junction diode.
$V_{SD}$	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 75A, V_{GS} = 0V $ §
t <sub>rr</sub>	Reverse Recovery Time		42	63	no 1	$T_J = 25^{\circ}C$ $V_R = 64V$ ,
			49	74		$T_J = 125^{\circ}C$ $I_F = 75A$
$Q_{rr}$	Reverse Recovery Charge		65	98		$T_J = 25^{\circ}C$ di/dt = 100A/ $\mu$ s $\odot$
			92	140	] '''	$T_J = 125^{\circ}C$
I <sub>RRM</sub>	Reverse Recovery Current		2.6		Α	$T_J = 25^{\circ}C$
t <sub>on</sub>	Forward Turn-On Time	Intrinsi	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)			

### Notes:

- temperature. Package limitation current is 75A.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- $R_G$  = 25  $\!\Omega,\,I_{AS}$  = 75 A,  $V_{GS}$  =10 V. Part not recommended for use above this value.
- $\textcircled{4} \quad I_{SD} \leq 75 A, \ di/dt \leq 500 A/\mu s, \ V_{DD} \leq V_{(BR)DSS}, \ T_J \leq 175 ^{\circ} C.$
- ⑤ Pulse width  $\leq 400\mu s$ ; duty cycle  $\leq 2\%$ .
- ① Calculated continuous current based on maximum allowable junction ⑥ Coss eff. (TR) is a fixed capacitance that gives the same charging time as  $C_{\text{oss}}$  while  $V_{\text{DS}}$  is rising from 0 to 80%  $V_{\text{DSS}}.$ 
  - O Coss eff. (ER) is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .
  - ® R<sub>θ</sub> is measured at T<sub>J</sub> approximately 90°C.

### Qualification Information<sup>†</sup>

		Automotive (per AEC-Q101) ††				
Qualification	Level	Comments: This part number(s) passed Automotive qualification level is granted extension of the higher Automotive level.				
Moisture Ser	nsitivity Level	3L-TO-220 N/A				
	Machine Model		Class M4(425V)			
			(per AEC-Q101-002)			
505	Human Body Model		Class H2(4000V)			
ESD		(per AEC-Q101-001)				
Charged Device Model		Class C5 (1125V)				
		(per AEC-Q101-005)				
RoHS Compl	liant	Yes				

<sup>†</sup> Qualification standards can be found at International Rectifier's web site: http://www.irf.com/

<sup>††</sup> Exceptions to AEC-Q101 requirements are noted in the qualification report.

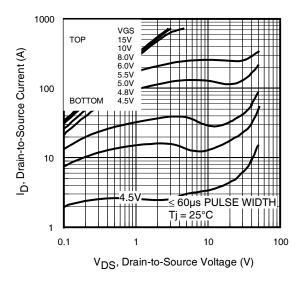


Fig 1. Typical Output Characteristics

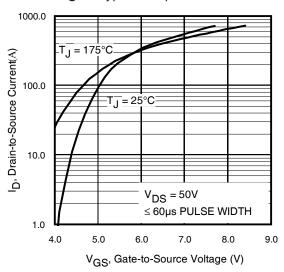


Fig 3. Typical Transfer Characteristics

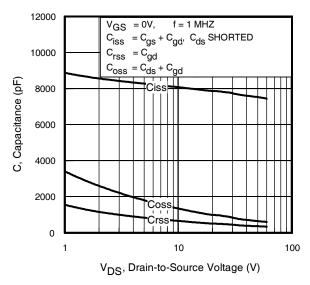


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

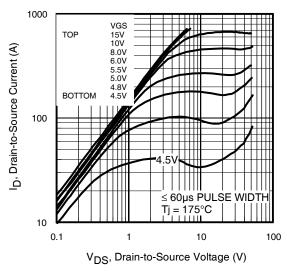


Fig 2. Typical Output Characteristics

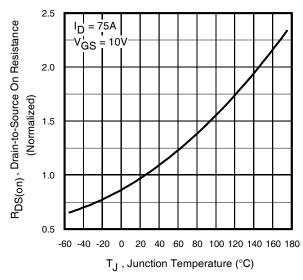
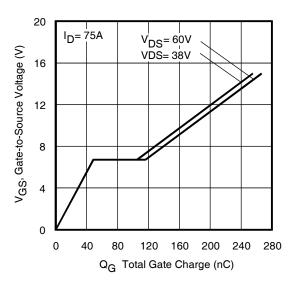
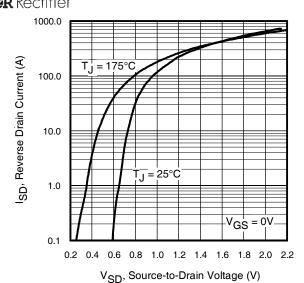


Fig 4. Normalized On-Resistance vs. Temperature



**Fig 6.** Typical Gate Charge vs. Gate-to-Source Voltage www.irf.com



**Fig 7.** Typical Source-Drain Diode Forward Voltage

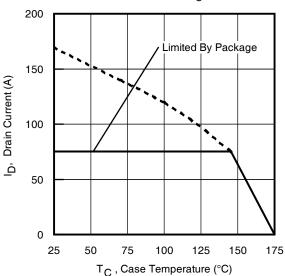


Fig 9. Maximum Drain Current vs.
Case Temperature

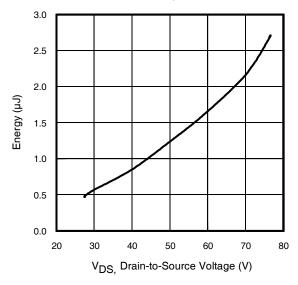


Fig 11. Typical C<sub>OSS</sub> Stored Energy

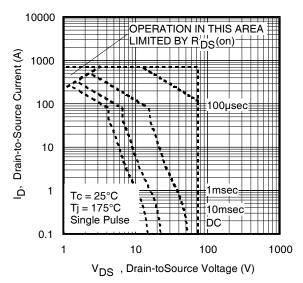


Fig 8. Maximum Safe Operating Area

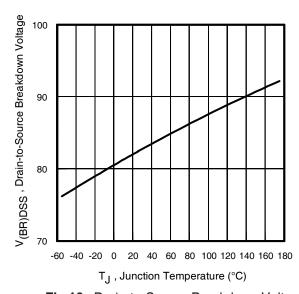


Fig 10. Drain-to-Source Breakdown Voltage

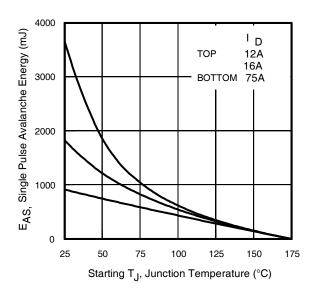


Fig 12. Maximum Avalanche Energy Vs. DrainCurrent

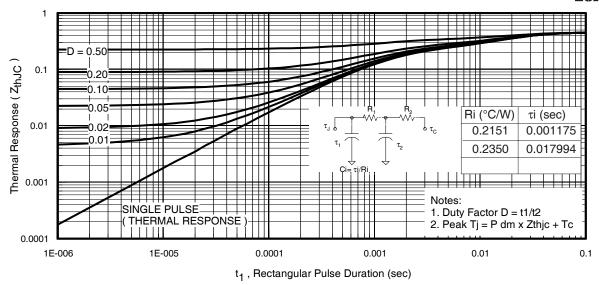


Fig 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case

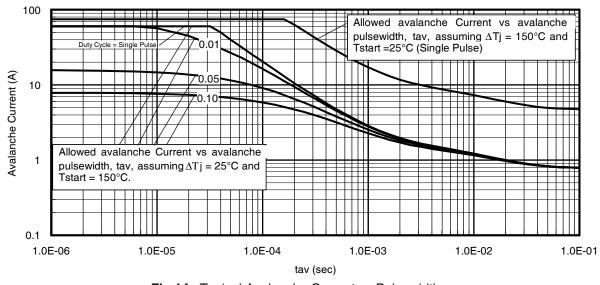


Fig 14. Typical Avalanche Current vs. Pulsewidth

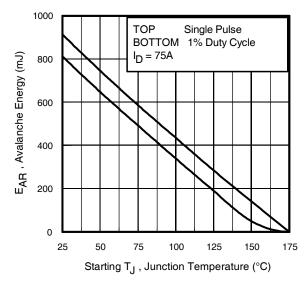


Fig 15. Maximum Avalanche Energy vs. Temperature

## Notes on Repetitive Avalanche Curves , Figures 14, 15: (For further info, see AN-1005 at www.irf.com)

1. Avalanche failures assumption:

Purely a thermal phenomenon and failure occurs at a temperature far in excess of  $T_{jmax}$ . This is validated for every part type.

- 2. Safe operation in Avalanche is allowed as long as neither  $T_{jmax}$  nor  $I_{av\ (max)}$  is exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 22a, 22b.
- 4. P<sub>D (ave)</sub> = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I<sub>av</sub> = Allowable avalanche current.
- 7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed  $T_{jmax}$  (assumed as 25°C in Figure 14, 15).

 $t_{av}$  = Average time in avalanche.

D = Duty cycle in avalanche =  $t_{av} \cdot f$ 

 $Z_{th,JC}(D, t_{av})$  = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D~(ave)} &= 1/2~(~1.3 \cdot BV \cdot I_{av}) = \triangle T/~Z_{thJC} \\ I_{av} &= 2\triangle T/~[1.3 \cdot BV \cdot Z_{th}] \\ E_{AS~(AR)} &= P_{D~(ave)} \cdot t_{av} \end{split}$$

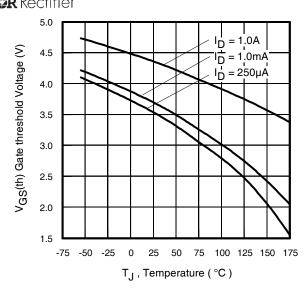


Fig 16. Threshold Voltage Vs. Temperature

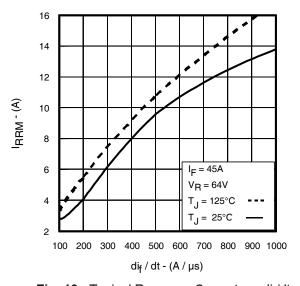


Fig. 18 - Typical Recovery Current vs. di<sub>f</sub>/dt

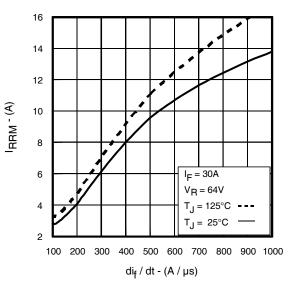


Fig. 17 - Typical Recovery Current vs. di<sub>f</sub>/dt

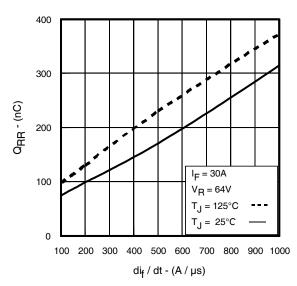


Fig. 19 - Typical Stored Charge vs. dif/dt

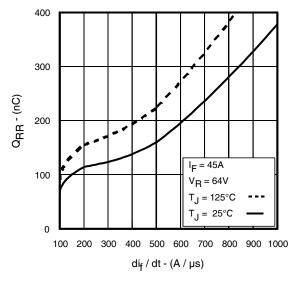


Fig. 20 - Typical Stored Charge vs. dif/dt

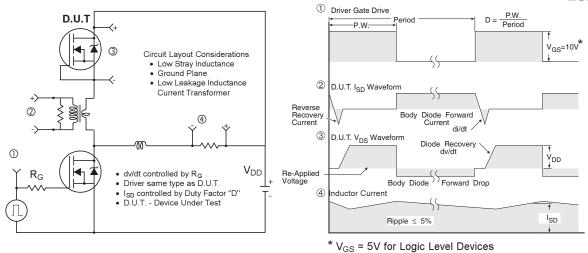


Fig 21. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

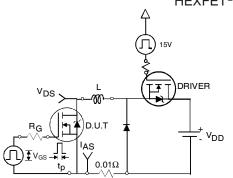


Fig 22a. Unclamped Inductive Test Circuit

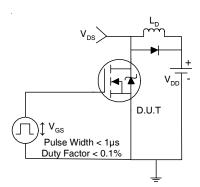


Fig 23a. Switching Time Test Circuit

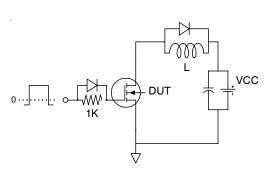


Fig 24a. Gate Charge Test Circuit

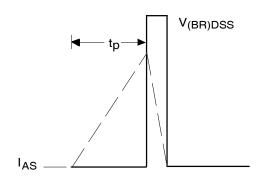


Fig 22b. Unclamped Inductive Waveforms

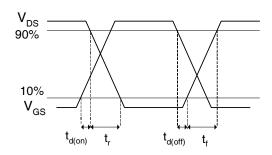


Fig 23b. Switching Time Waveforms

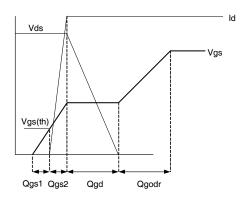
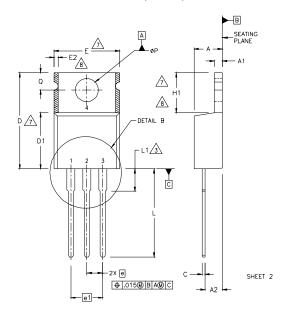
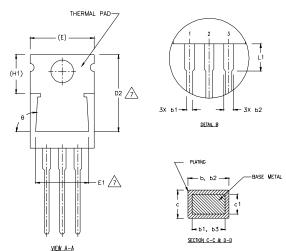


Fig 24b. Gate Charge Waveform

# TOR Rectifier TO-220AB Package Outline

Dimensions are shown in millimeters (inches)





### NOTES:

SYMBOL

Α1 A2

ь1

b2

ь3

c1

D

D1

D2

E1

e1

H1

øΡ

Q

- DIMENSIONING AND TOLERANCING PER ASME Y14.5 M- 1994.
- DIMENSIONS ARE SHOWN IN INCHES [MILLIMETERS]. LEAD DIMENSION AND FINISH UNCONTROLLED IN L1
- DIMENSION D & E DO NOT INCLUDE MOLD FLASH, MOLD FLASH SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- DIMENSION b1 & c1 APPLY TO BASE METAL ONLY. CONTROLLING DIMENSION: INCHES.
- THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS E,H1,D2 & E1

MAX

4.82

1.40

2.92

1.01

0.96

1.77

1.73

0.61

0.56

16.51

9.02

12,88

10.66

8.89

14,73

6.35

4.08

3,42

DIMENSIONS

INCHES

MAX

.190

.055

.115

.040

.038

.070

.068

.024

.022

.650

.355

.507

,420

.350

.580

.250

,161

.135

MIN.

.140

.020

.080

.015

.015

.045

.045

.014

.014

.560

.330

.480

.380

.330

.230

.500

.139

.100

NOTES

5

5

4

4,7

7,8

3

DIMENSION E2 X H1 DEFINE A ZONE WHERE STAMPING AND SINGULATION IRREGULARITIES ARE ALLOWED.

MILLIMETERS

MIN.

3.56

0.51

2.04

0.38

0.38

1.15

1.15

0.36

0.36

14.22

8.38

12,19

9.66

8.38

12.70

3.54

2.54

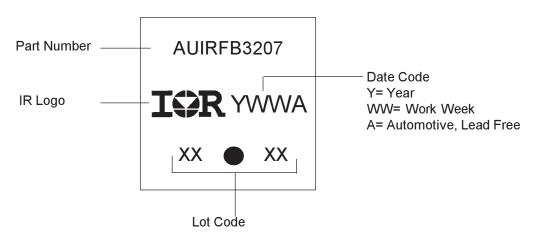
### HEXFET

### IGBTs, CoPACK

1.- GATE 2.- COLLECTOR 3.- EMITTER

- DIODES
- 1.- ANODE/OPEN 2.- CATHODE 3.- ANODE

## TO-220AB Part Marking Information



**Ordering Information** 

Base part	Package Type	Standard Pack		Complete Part Number
		Form	Quantity	
AUIRFB3207	TO-220	Tube	50	AUIRFB3207



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http://www.irf.com/technical-info/

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